

200V 18A Advanced N-Ch Power MOSFET

FEATURES

- High Voltage : $BV_{DSS}=200V(\text{Min.})$
- Low C_{rss} : $C_{rss}=55pF(\text{Typ.})$
- Low gate charge : $Q_g=22nC(\text{Typ.})$
- Low $R_{DS(on)}$: $R_{DS(on)}=0.17\Omega(\text{Max.})$

Marking Information

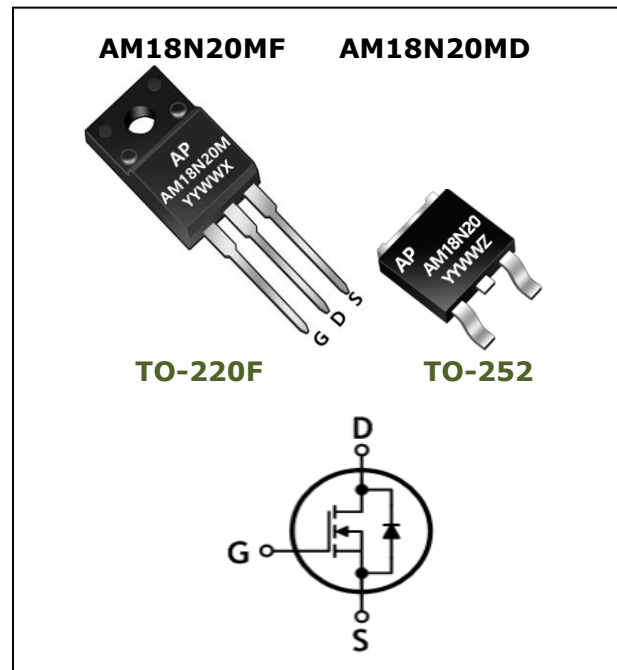
Row 1 : AP

Row 2 : Product Information

Row 3 : Date Code

- YY : Year Code
- WW : Week Code

Ordering Information



Part No	Package	Packing	Finish	Halogen	Packing Unit
AM18N20MF	TO-220F	Tube	Sn	Free	5,000EA
AM18N20MD	TO-252	13" REEL & Tape	Sn	Free	2,500EA

Maximum Ratings (Tc=25 °C, unless otherwise noted)

Characteristic	Symbol	Rating	Unit
Drain-source voltage	V_{DSS}	200	V
Gate-source voltage	V_{GSS}	± 30	V
Drain current (DC)*	I_D	$T_C = 25^\circ C$	A
		$T_C = 100^\circ C$	
Drain current (Pulsed)*	I_{DM}	72	A
Power Dissipation	P_D	TO-220F	W
		TO-252	
Avalanche current (Single) (Note 2)	I_{AS}	18	A
Single pulsed avalanche energy (Note 2)	E_{AS}	453	mJ
Avalanche current (Repetitive) (Note 1)	I_{AR}	18	A
Repetitive avalanche energy (Note 1)	E_{AR}	13.9	mJ
Junction temperature	T_J	150	$^\circ C$
Storage temperature range	T_{stg}	-55~150	

*Limited only maximum junction temperature

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Thermal Characteristic (TO-220F)

Characteristic	Symbol	Rating	Unit
Thermal resistance, junction to case	$R_{th(j-c)}$	Max. 2.5	$^{\circ}\text{C/W}$
Thermal resistance, junction to ambient	$R_{th(j-a)}$	Max. 62.5	

Electrical Characteristics ($T_C=25^{\circ}\text{C}$, unless otherwise noted)

Characteristic	Symbol	Test Condition	Min.	Typ.	Max.	Unit
Drain-source breakdown voltage	BV_{DSS}	$I_D = 250\mu\text{A}$, $V_{GS} = 0$	200	-	-	V
Gate threshold voltage	$V_{GS(th)}$	$I_D = 250\mu\text{A}$, $V_{DS} = V_{GS}$	2	-	4	V
Drain-source cut-off current	I_{DSS}	$V_{DS} = 200\text{V}$, $V_{GS} = 0\text{V}$	-	-	1	μA
		$V_{DS} = 200\text{V}$, $T_C=150^{\circ}\text{C}$	-	-	100	
Gate leakage current	I_{GSS}	$V_{DS} = 0\text{V}$, $V_{GS} = \pm 30\text{V}$	-	-	± 100	nA
Drain-source on-resistance (Note 4)	$R_{DS(ON)}$	$V_{GS} = 10\text{V}$, $I_D = 9.0\text{A}$	-	0.14	0.17	Ω
Forward transfer conductance (Note 4)	g_{fs}	$V_{DS} = 10\text{V}$, $I_D = 9.0\text{A}$	-	10.5	-	S
Input capacitance	C_{iss}	$V_{DS} = 25\text{V}$, $V_{GS} = 0\text{V}$, $f = 1.0\text{MHz}$	-	942	1240	pF
Output capacitance	C_{oss}		-	227	-	
Reverse transfer capacitance	C_{rss}		-	55	-	
Turn-on delay time (Note 3,4)	$T_{d(on)}$	$V_{DS} = 125\text{V}$, $I_D = 18\text{A}$, $R_G = 25\Omega$	-	15	-	ns
Rise time (Note 3,4)	T_r		-	130	-	
Turn-off delay time (Note 3,4)	$t_{d(off)}$		-	135	-	
Fall time (Note 3,4)	t_f		-	105	-	
Total gate charge (Note 3,4)	Q_g	$V_{DS} = 160\text{V}$, $V_{GS} = 10\text{V}$, $I_D = 18\text{A}$	-	22	28	nC
Gate-source charge (Note 3,4)	Q_{gs}		-	6.6	-	
Gate-drain charge (Note 3,4)	Q_g		-	7.2	-	

Source-Drain Diode Ratings and Characteristics ($T_C=25^{\circ}\text{C}$, unless otherwise noted)

Characteristic	Symbol	Test Condition	Min.	Typ.	Max.	Unit
Source current (DC)	I_S	Integral reverse diode in the MOSFET	-	-	18	A
Source current (Pulsed) (Note 1)	I_{SM}		-	-	72	A
Forward voltage (Note 4)	V_{SD}	$V_{GS} = 0\text{V}$, $I_S = 12\text{A}$	-	-	1.4	V
Reverse recovery time	t_{rr}	$I_S = 12\text{A}$, $V_{GS} = 0\text{V}$ $dI_F/dt = 100\text{A}/\mu\text{s}$	-	208	-	ns
Reverse recovery charge	Q_{rr}		-	1.63	-	μC

Note :

1. Repetitive rating : Pulse width limited by maximum junction temperature.
2. $L=2.1\text{mH}$, $I_{AS}=18\text{A}$, $V_{DD}=50\text{V}$, $R_G=25\Omega$, Starting $T_J=25^{\circ}\text{C}$
3. Pulse Test : Pulse width $\leq 300\mu\text{s}$, Duty cycle $\leq 2\%$
4. Essentially independent of operating temperature

REV. 02



Typical Electrical Characteristic

Fig. 1 $I_D - V_{DS}$

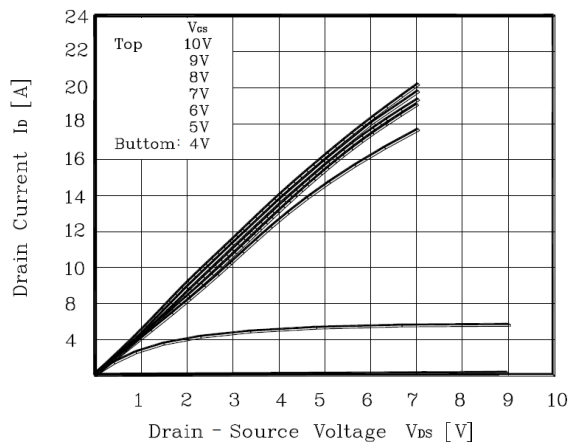


Fig. 2 $I_D - V_{GS}$

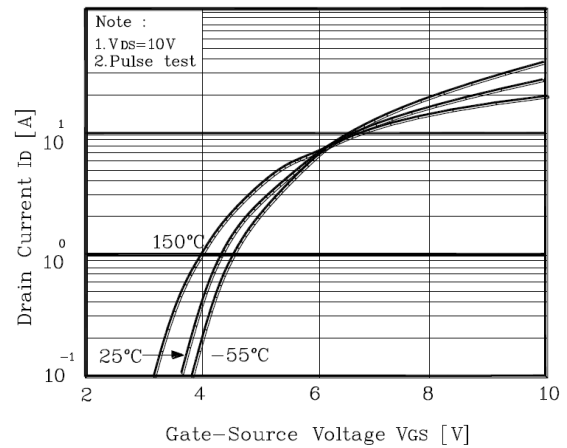


Fig. 3 $R_{DS(on)} - I_D$

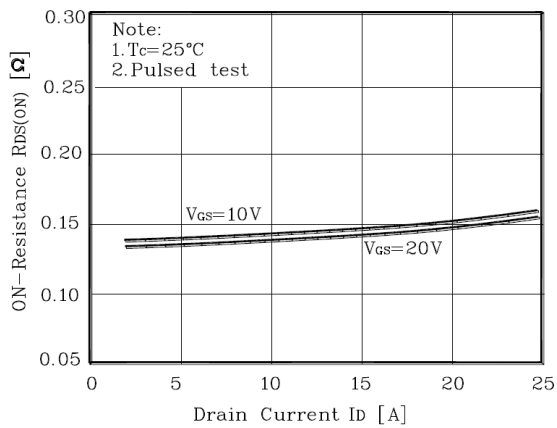


Fig. 4 $I_S - V_{SD}$

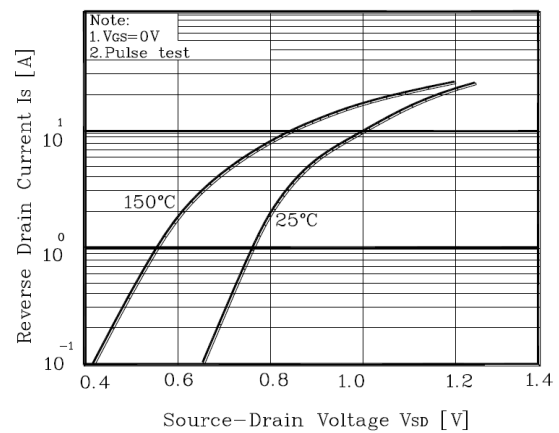




Fig. 5 Capacitance - V_{DS}

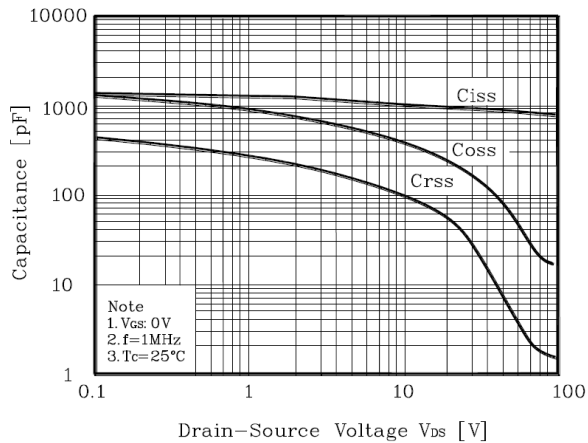
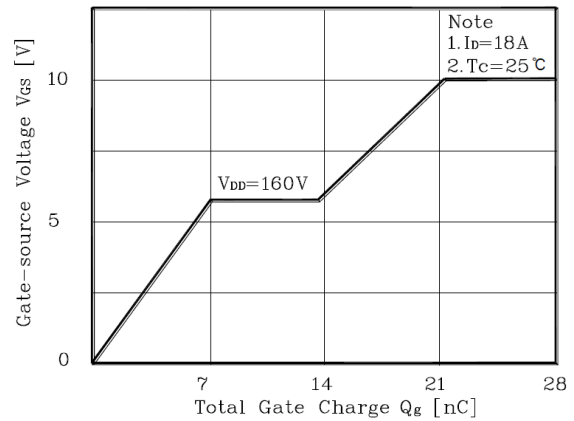


Fig. 6 V_{GS} - Q_G



Typical Electrical Characteristic

Fig. 7 V_{DS} - T_J

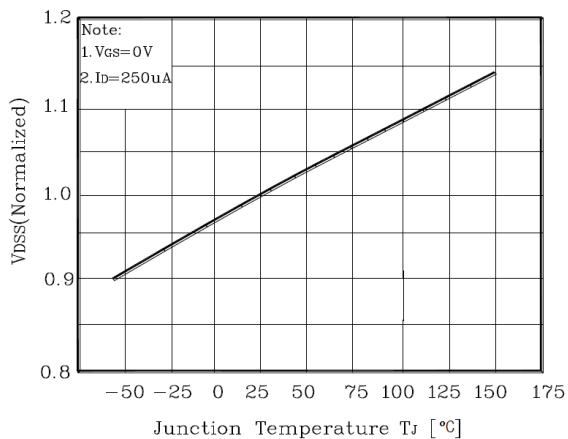


Fig. 8 $R_{DS(on)}$ - T_J

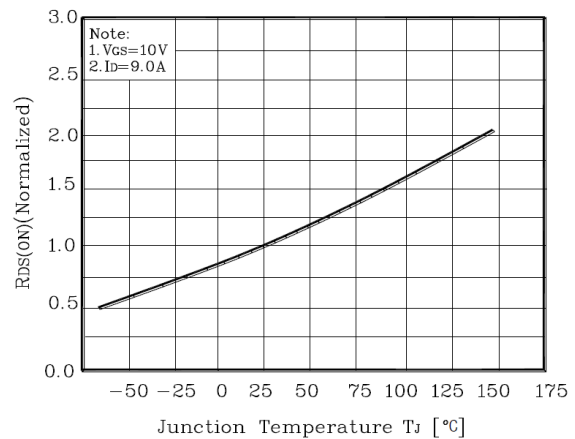


Fig. 9 I_D - T_c

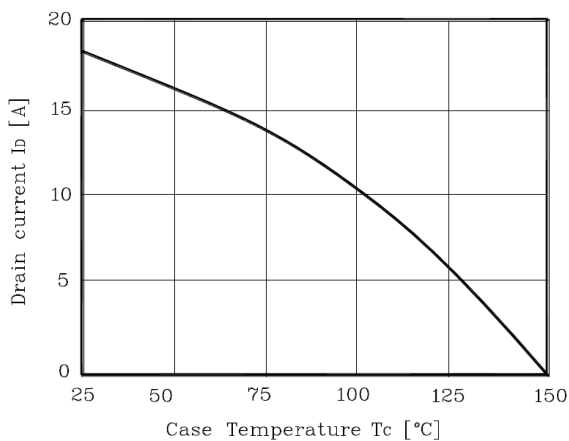


Fig. 10 Safe Operating Area

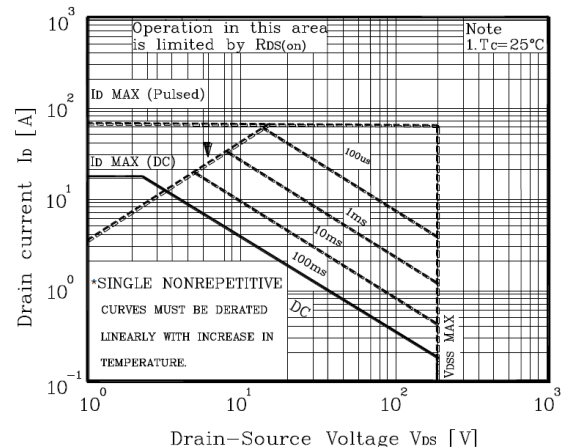




Fig. 11 Gate Charge Test Circuit & Waveform

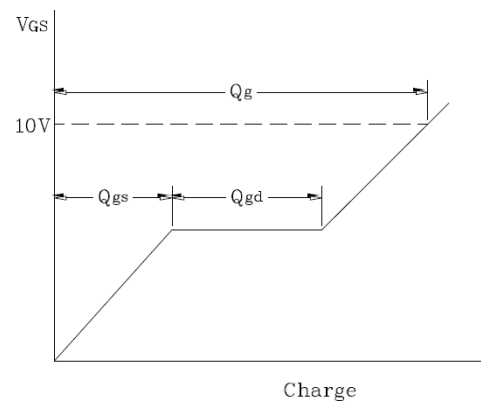
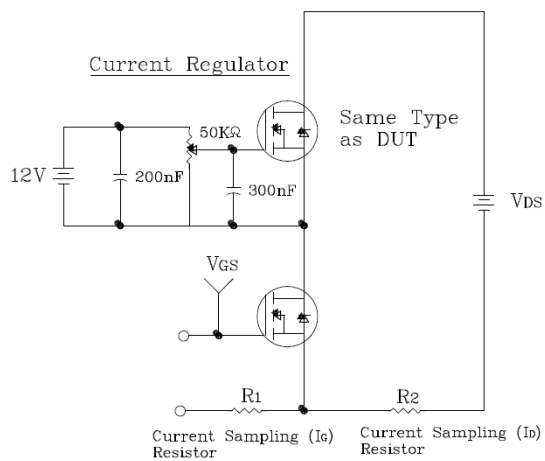


Fig. 12 Resistive Switching Test Circuit & Waveform

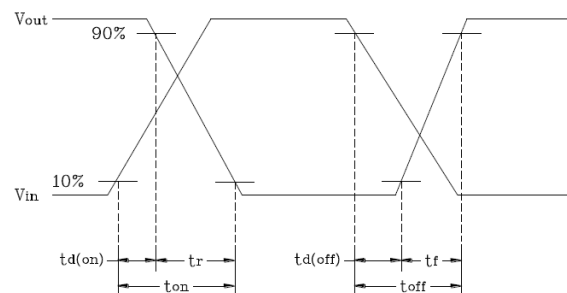
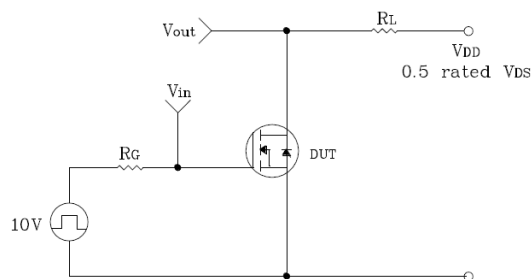




Fig. 13 E_{AS} Test Circuit & Waveform

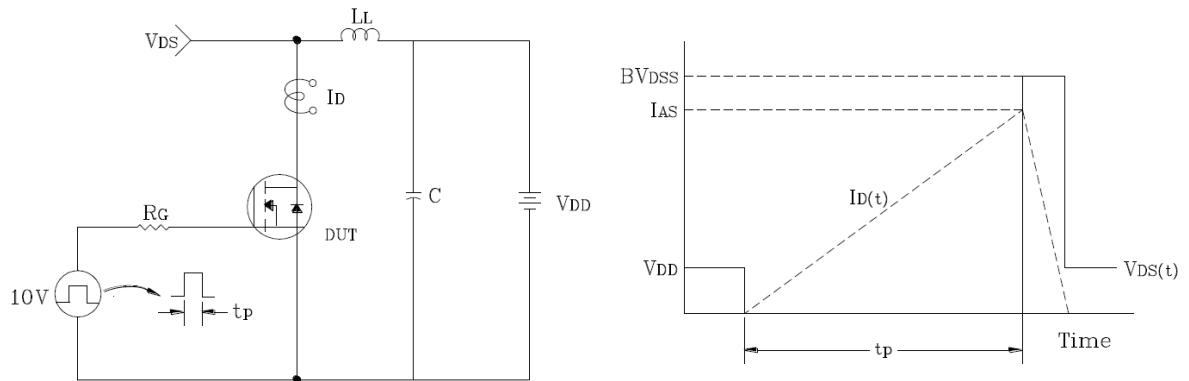
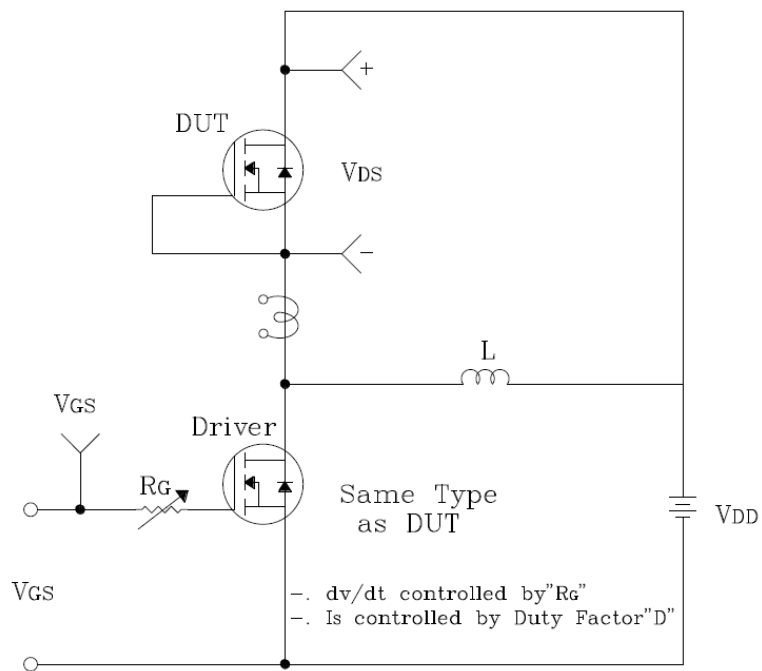
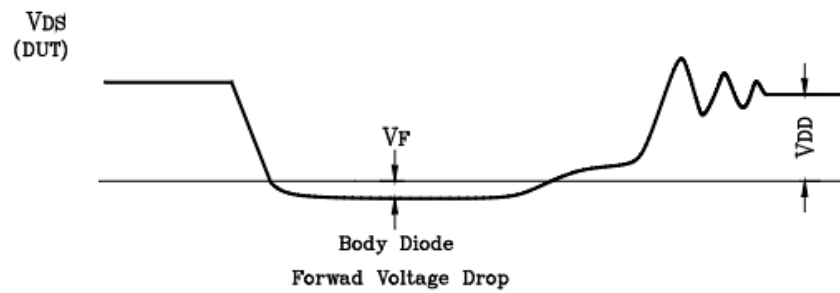
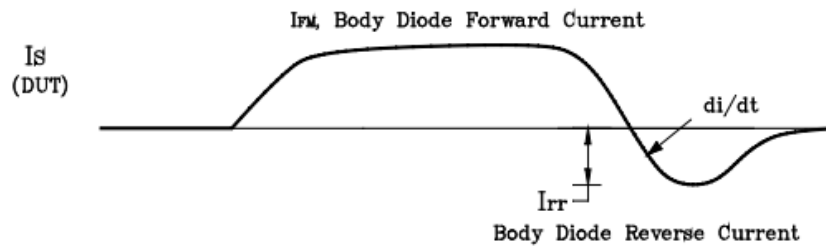
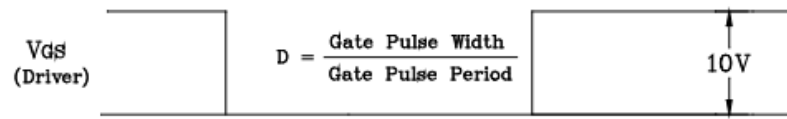


Fig. 14 Diode Reverse Recovery Time Test Circuit & Waveform

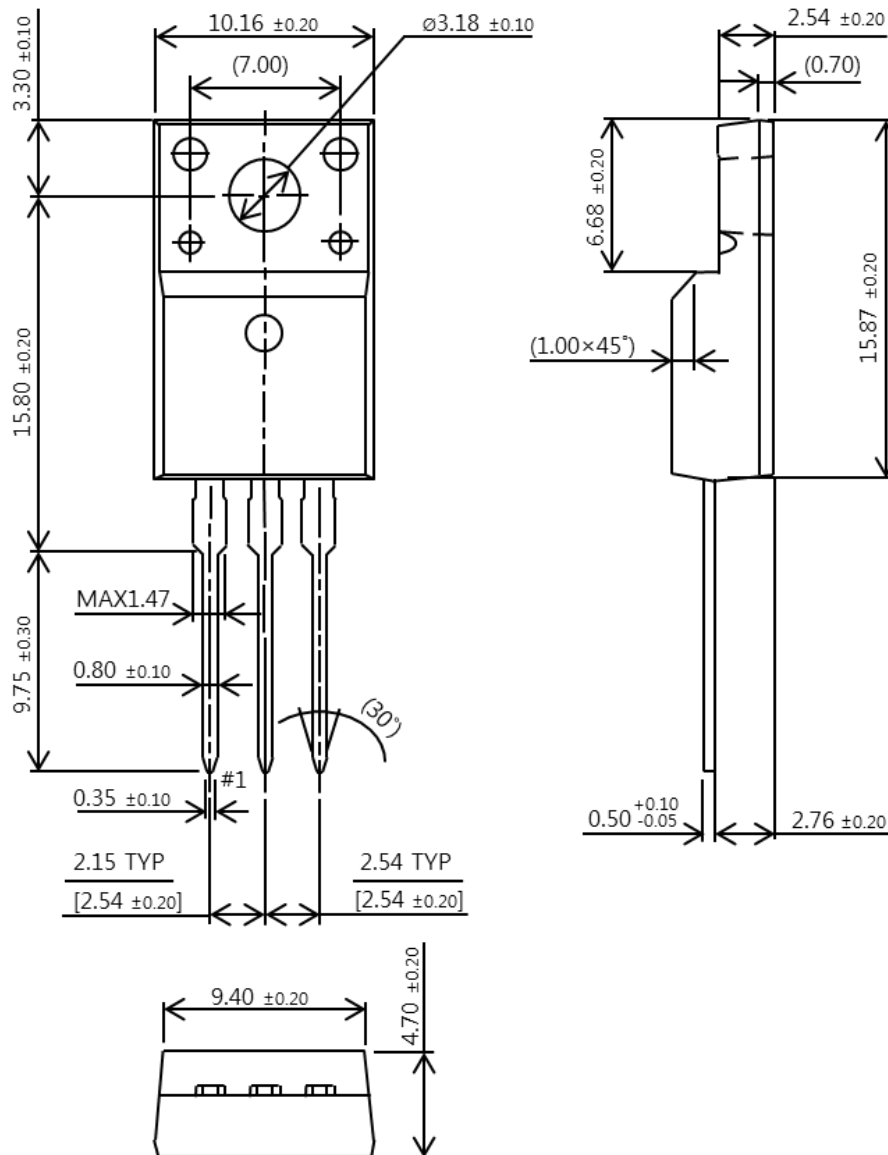






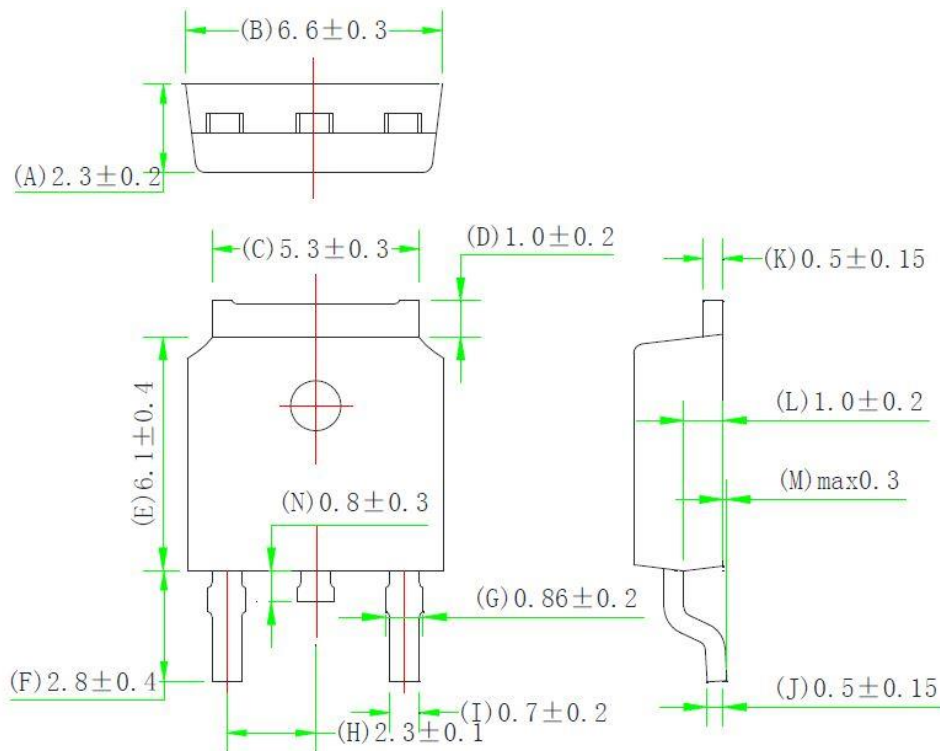
Package Dimensions

TO-220F(unit : mm)





TO-252





Revision History

No	Date	Contents
0	2021-04-25	Initial Brief Datasheet Release

<http://www.apsemi.com>

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